

Abstracts

A New Method for Measuring Dielectric Properties of Material Media Using a Microstrip Cavity

T. Itoh and R. Mittra. "A New Method for Measuring Dielectric Properties of Material Media Using a Microstrip Cavity." 1973 G-MTT International Microwave Symposium Digest of Technical Papers 73.1 (1973 [MWSYM]): 138-139.

A new method for non-destructive testing has been developed for measuring the dielectric constant and the dissipation factor of a slab-type material using a microstrip line cavity. The method has several advantages and yields accurate results with a simple procedure.

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